



A Statistical Approach to Product Quality Assurance

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Topics to be covered

- Purpose of Quality Assurance
- Classical Approach to Quality Assurance
 - How It Works
 - Deficiencies of Classical Approach
- Defect Model Approach to Quality Assurance
 - Premise
 - How It Works
 - Types of Defects
 - Benefits of this Quantitative Approach
- Conclusion



Purpose of Quality Assurance

- To provide staff & management insight into processes being used and work products being built
 - Determine process adherence
 - Evaluate work products during development and prior to delivery



Classical Approach to Quality Assurance

- Separate group from developers
 - A way of insuring independence
- QA group examines/reads the work product to be evaluated
 - Often after the work product is completed
 - Defects found are costly to correct
- QA group typically does not have the domain knowledge to judge technical quality
 - Technical quality not determined
 - Determine if formatted properly
 - Meets standards imposed

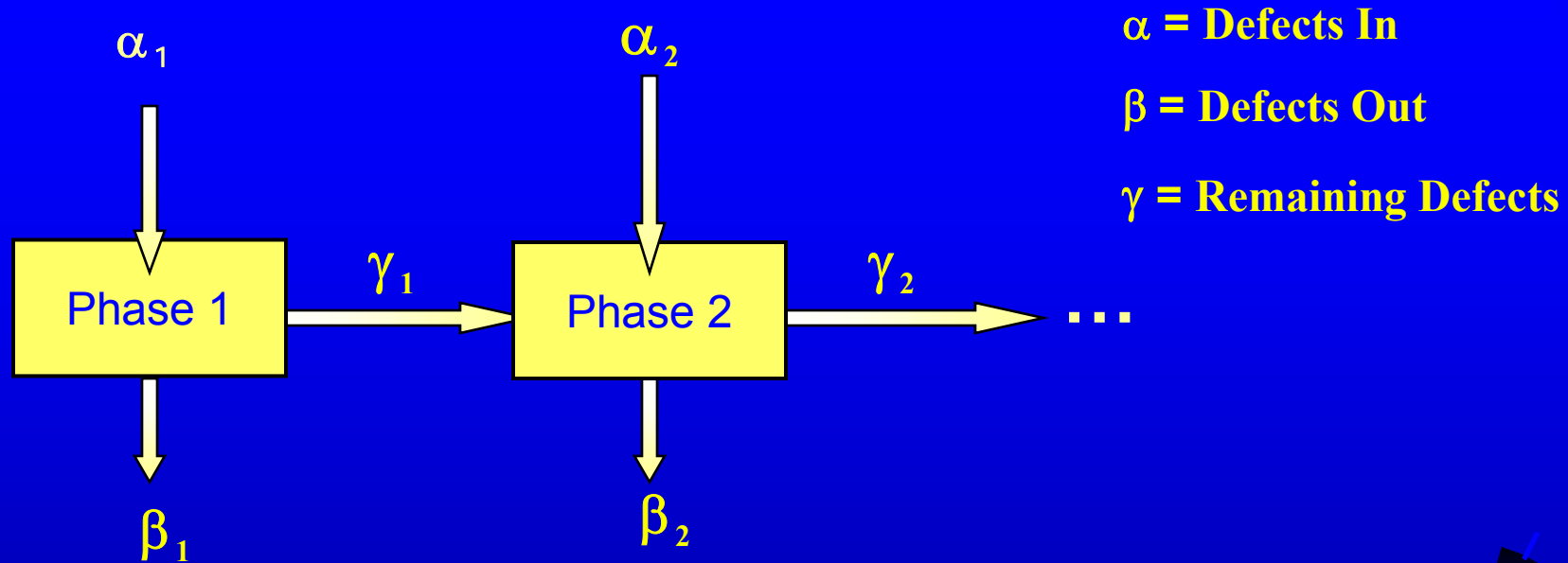


Premise

- Products are created by executing processes
- In a mature organization, process performance is known, repeatable and controlled
- Defects are inserted at statistically known rates
- Therefore by monitoring defects detected
 - Estimate of defects remaining in product can be made
 - A statement of the product quality can be quantitatively made
 - Corrective action can be taken early in the life cycle
 - Least costly to correct



Defect Modeling



$$\alpha_1 = \beta_1 + \gamma_1$$

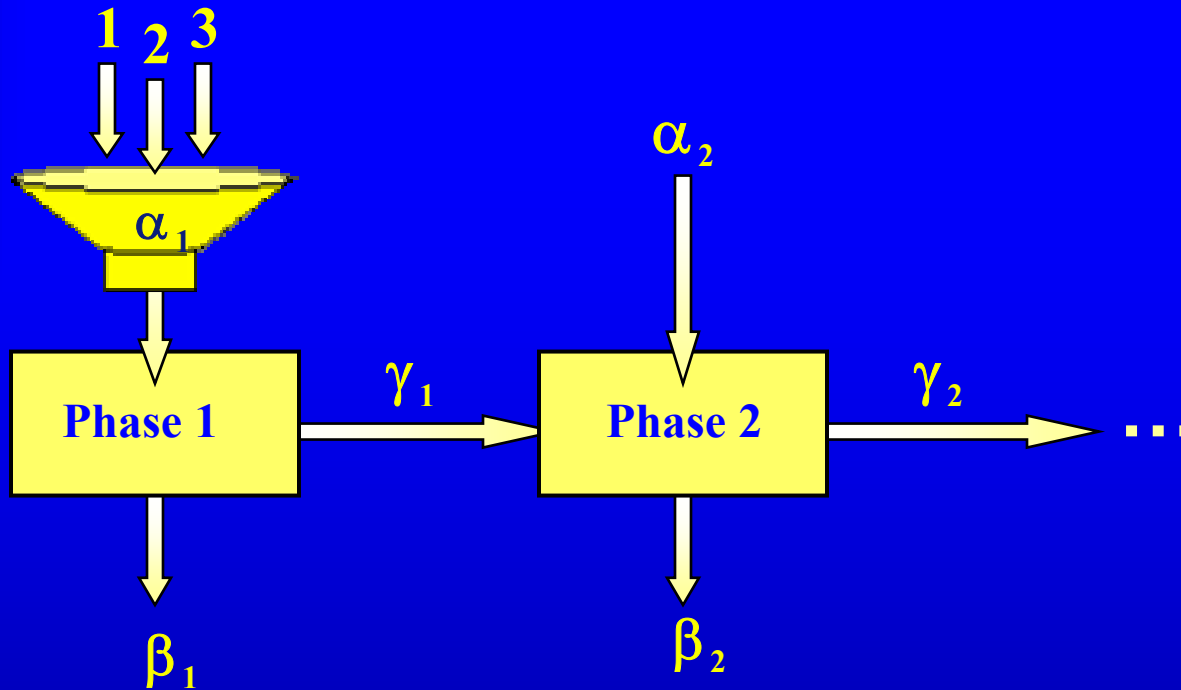
$$\gamma_1 = \alpha_1 - \beta_1$$

$$\alpha_2 + \gamma_1 = \beta_2 + \gamma_2$$

$$\gamma_2 = \alpha_2 + \gamma_1 - \beta_2$$

“Defects In” is known, “Defects Out” is monitored --> Therefore
“Remaining Defects” left in product can be determined

Defect Modeling



1 = New

2 = Mod

3 = Revised

α = Defects In

β = Defects Out

γ = Remaining Defects

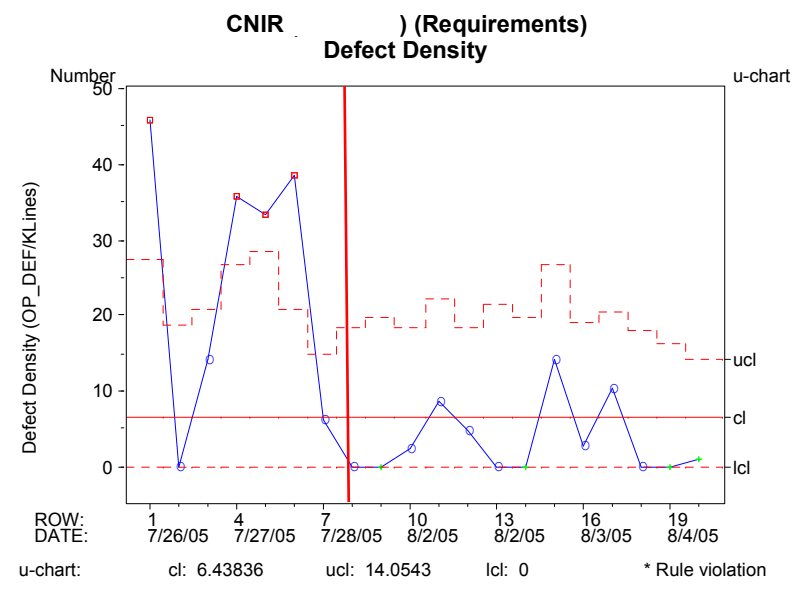
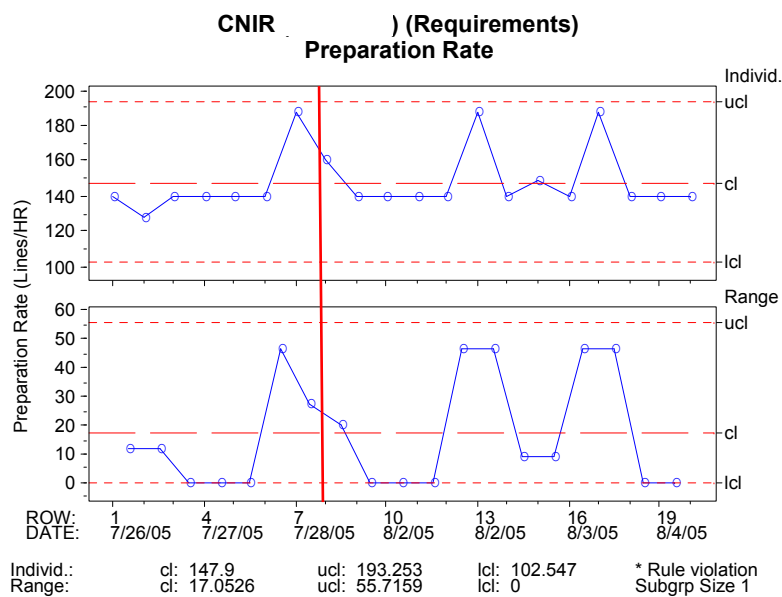
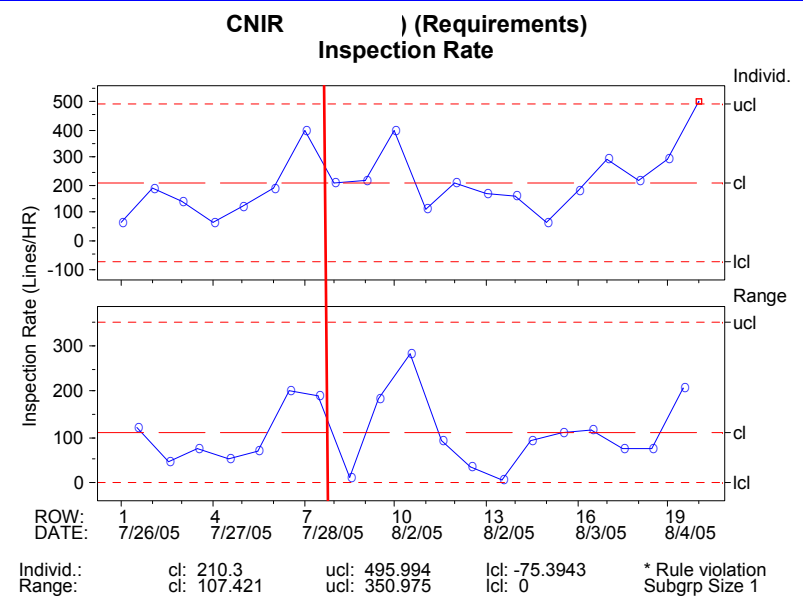
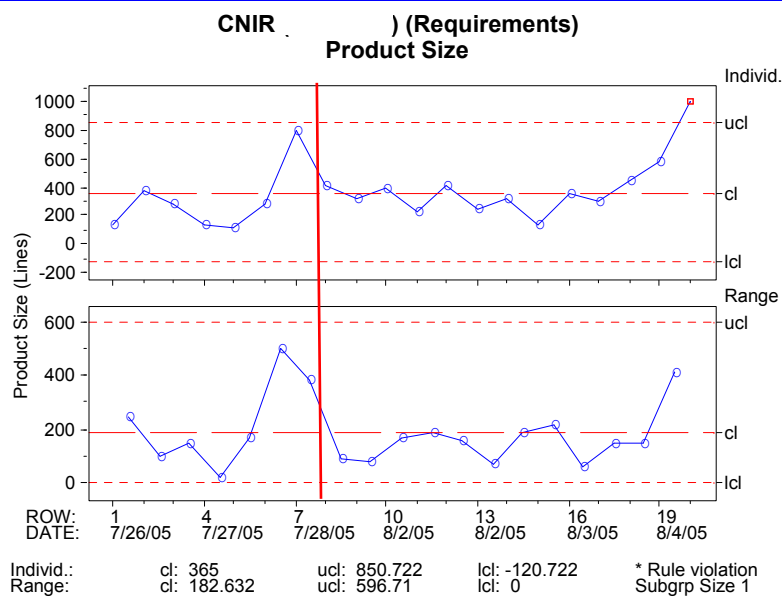
$$\alpha_1 = \beta_1 + \gamma_1$$

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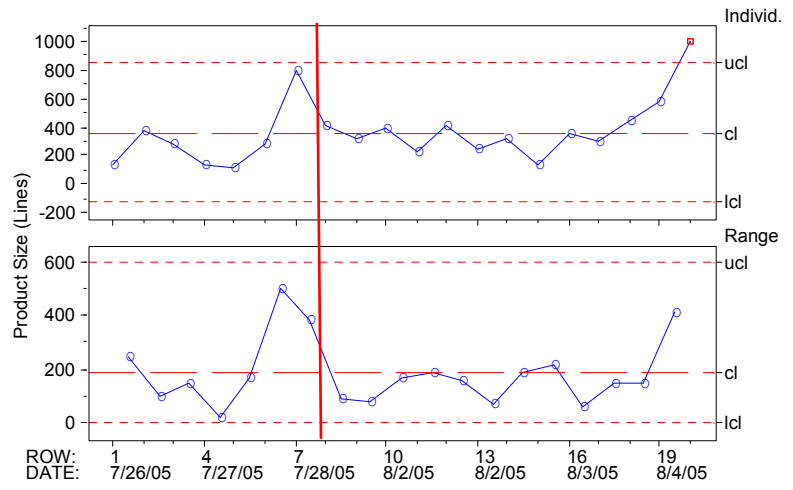
$$\gamma_2 = \alpha_2 + \gamma_1 - \beta_2$$





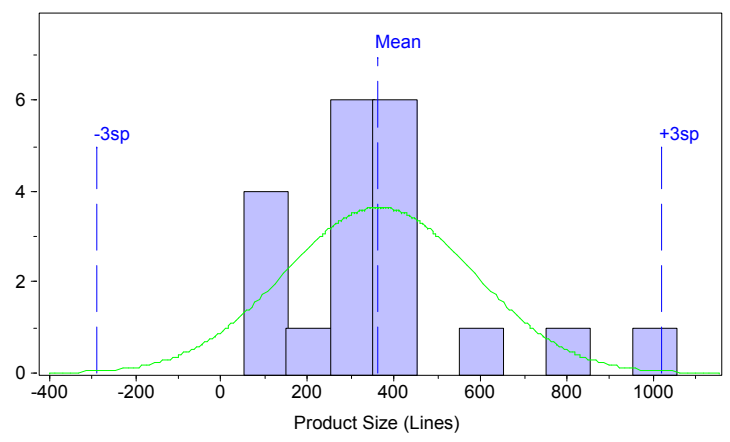
Causal Analysis

CNIR (Requirements) Product Size



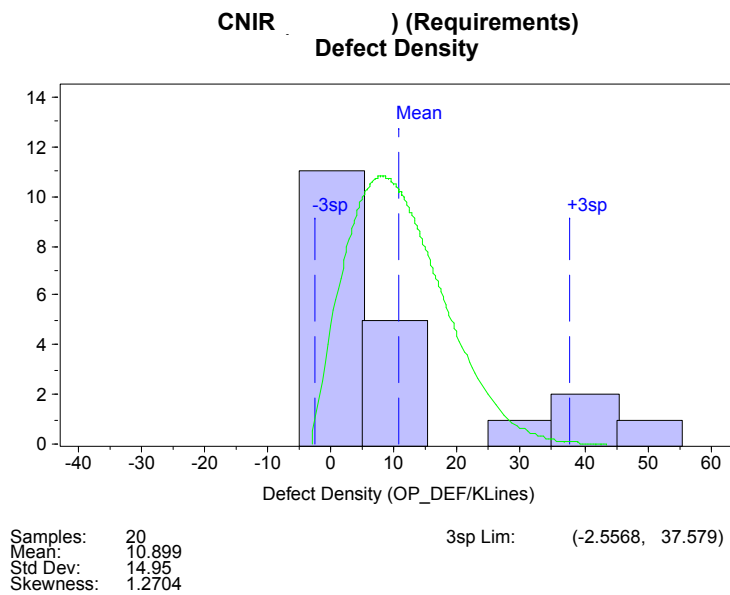
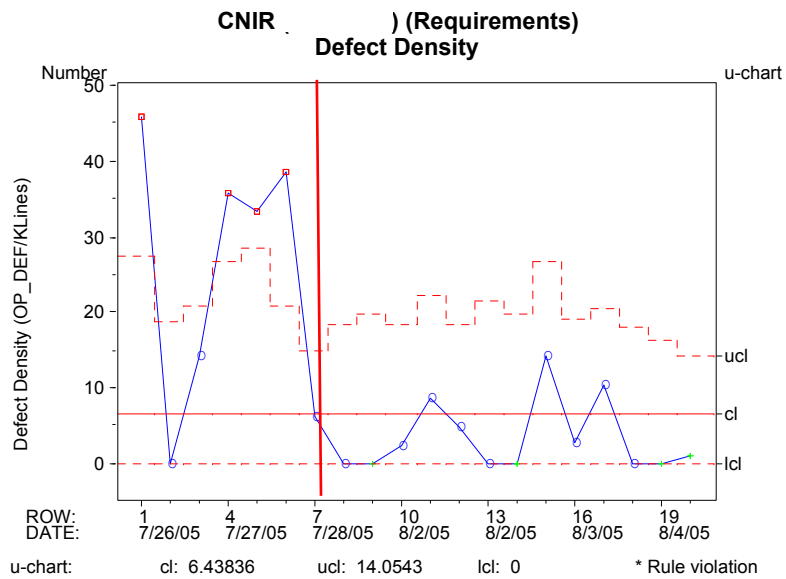
ROW: 1
 DATE: 7/26/05 7/27/05 7/28/05 8/2/05 8/2/05 8/3/05 8/4/05
 Individ.: cl: 365 ucl: 850.722 lcl: -120.722 * Rule violation
 Range: cl: 182.632 ucl: 596.71 lcl: 0 Subgrp Size 1

CNIR (Requirements) Product Size

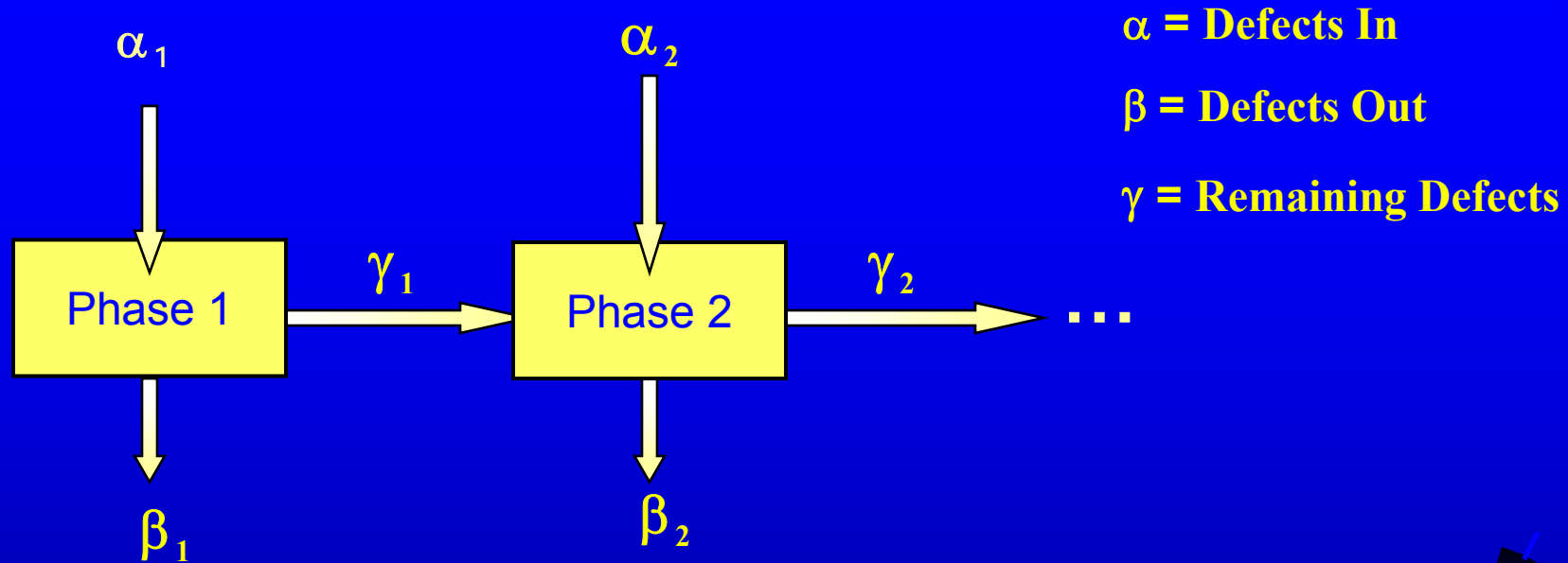


Samples: 20
 Mean: 365
 Std Dev: 218.73
 Skewness: 1.4814
 3sp Lim: (-291.2, 1021.2)

Causal Analysis



Defect Modeling



$$\alpha_1 = \beta_1 + \gamma_1$$

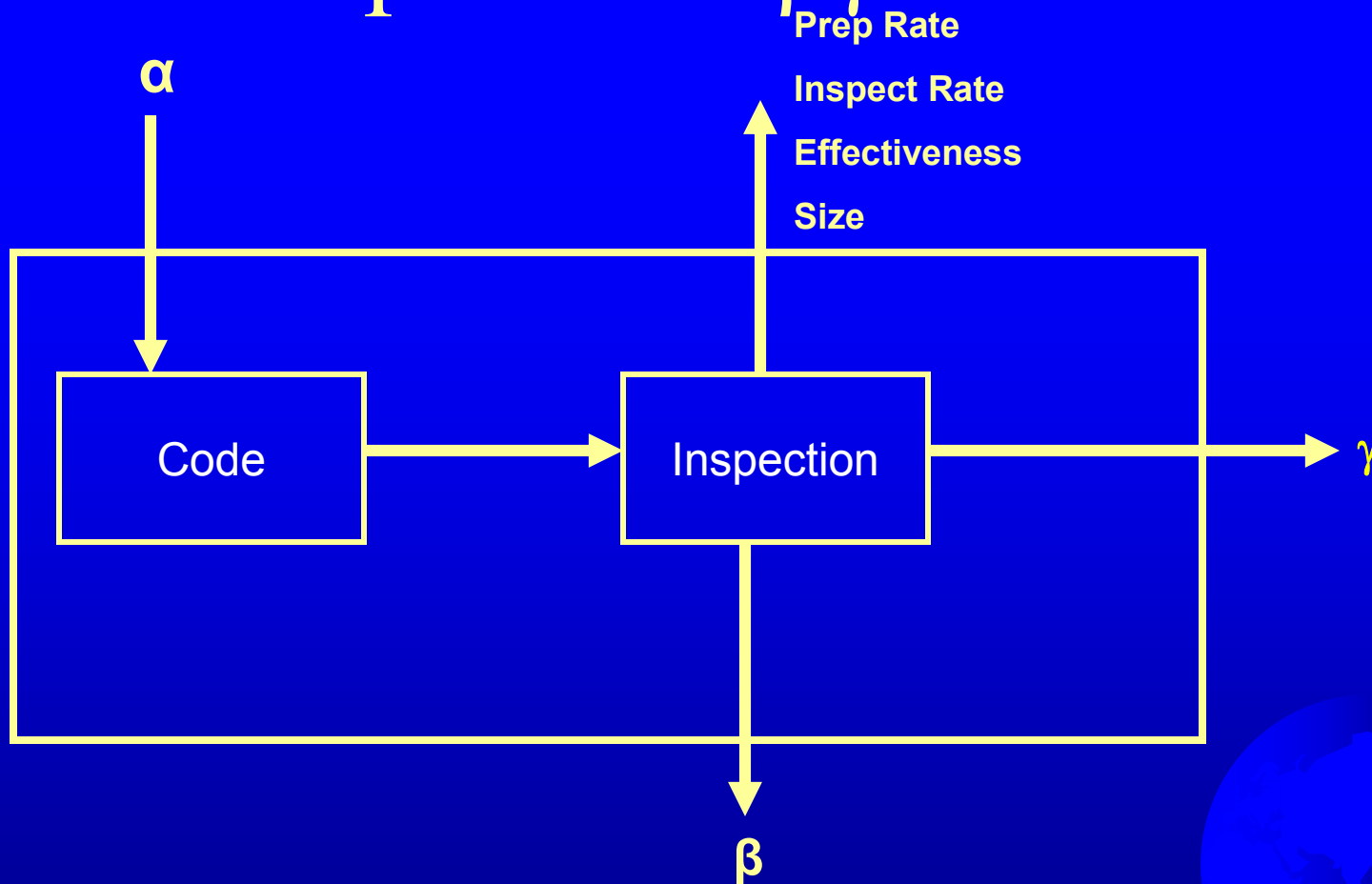
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Expanded $\alpha\beta\gamma$ Chart



Defect Detection Methods

- “Peer Reviews”
 - Inspections (Fagan)
 - Structured Walk-Through
 - Active Reviews
- Modeling and Simulation
- Testing
 - Unit
 - Integration
 - Formal/ Sell-off
- Various Effectiveness in Methods



Sources of Defect

- Ambiguous Requirements
- Incomplete Analysis of Requirements
- Misunderstood Requirements
- Poor Design
 - No Flexibility
 - Too General
- Error in Coding
- Complexity
- Miss-execution
- COTS
- Open Source



Types of Defects

- Logic (Most Prevalent)
- Computation
- Interface
 - External
 - Internal
- Data



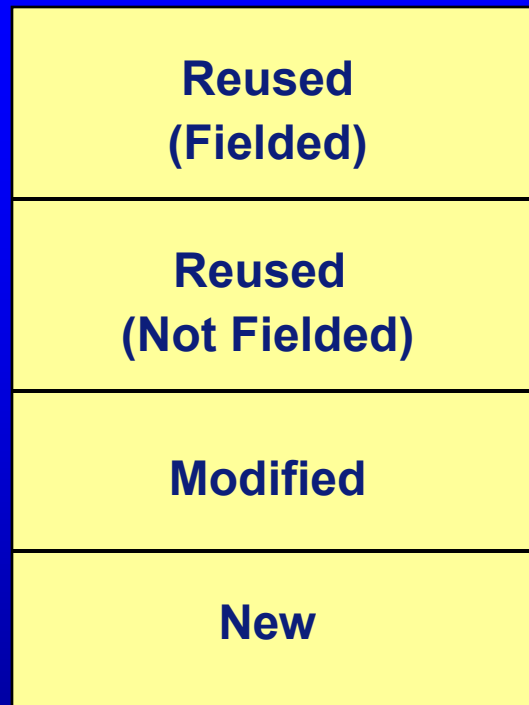
Acceptable Defect Levels

- Categories of Software:
 - Demonstration (Proof of Concept)
 - Windows
 - Military
 - DO-178B
 - 5 Categories f (affect of failure)
 - Manned Space Flight
- Level of latent defects permissible varies (Do not want to overkill; Too costly)



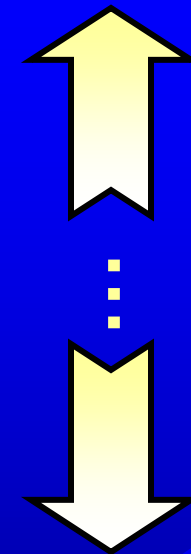
Defect Model (By the Numbers)

Know
the
Pedigree
of
Reused
Code



What is the Defect Density?

0.2 Defects/ KSLOC



25 Defects/ KSLOC

Not Simple



CNIR Defect Model

New Functionality

Phase	Insert	Detect
Requirements	46	37
Design	21	17
Coding	8	15
Test	0.2	≤ 4.6
FQT	0.1	≤ 2.5

CNIR #'s

CNIR Defect Model

Mod Functionality

Phase	Insert	Detect
Requirements	20	16
Design	21	17
Coding	5.8	10
Test	0.2	≤ 4.6
FQT	0.1	≤ 2.5

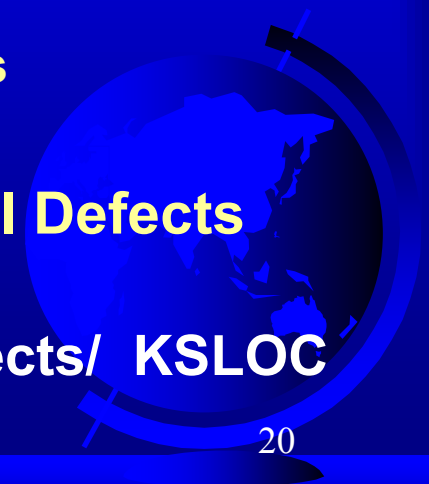
CNIR #'s

Defect Cost Example

10 K	Reused @ 0.2 Defects/ KSLOC	0.2 Defects
9 K	Reused Prototype @ 15 Defects/ KSLOC	30 Defects
7 K	Modified Significant @ 20 Defects/ KSLOC	40 Defects
5 K	New @ 25 Defects/ KSLOC	125 Defects

= 195.2 Total Defects

Therefore, 19.5 Defects/ KSLOC



Defect Cost Example (continued)

- 195 Defects in 9 KSLOC
 - @ 100% Fagan Coverage
 - 45 Fagan Inspections
 - @ 20 Man Hours/ Inspection
 - 900 Man Hours
 - 39 Defects
 - @ 20 Man Hours/ Defect
 - 780 Man Hours
 - @ 40 Man Hours/ Defect
 - 1,560 Man Hours
- Removing 156 Defects
- 39 Defects Remaining

Total Cost: 1,880 – 2,460 Man Hour

Code/ Unit Test/ Integration

At 2 SLOC/ Man Hour, Total Cost = 4,500 Man Hours



Defect Cost Example (continued)

- 195 Defects in 9 KSLOC
 - @ 50% Fagan Coverage
 - 23 Fagan Inspections
 - @ 20 Man Hours/ Inspection
 - 460 Man Hours
- Removing 62 Defects
- 133 Defects Remaining

- 133 Defects
 - @ 20 Man Hours/ Defect
 - 2,660 Man Hours
 - @ 40 Man Hours/ Defect
 - 5,320 Man Hours

Total Cost: 3,120 - 5,780 Man Hours



Benefits of Method

- Quality of product is estimated quantitatively as components are created
 - Defects least costly to correct
- Systemic problems identified and steps taken to prevent repeating defects
- Additional defect detection activities can be added if deemed necessary



Conclusion

- Defect Modeling and Statistical Control of Quality provides the following advantages over the classical method
 - Technical Product Quality is objectively evaluated by personnel with domain knowledge using a formal proven approach
 - Estimate of defects remaining in product can be made throughout the product lifecycle
 - Corrective action can be taken early in the life cycle
 - Least costly to correct
 - The quality of the end product is known
 - Additional defect detection activities can be added if deemed necessary
 - Trend analysis of defects and root cause analysis can lead to proactively preventing future defects not only on the project, but throughout the organization



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